

Search Notes	Application/Control No.	Applicant(s)/Patent Under Reexamination
	10659593	LEE, BAEK-WOON
	Examiner	Art Unit
	Sherman, Stephen G	2629

SEARCHED			
Class	Subclass	Date	Examiner
345	88,600,603-605,613,87-102	11/29/2006	SS
349	56,82,84,109,143	11/29/2006	SS
349	139	4/16/2007	SS

SEARCH NOTES			
Search Notes	Date	Examiner	
See attached search history			
Search Updated	11/29/2006	SS	
Search Updated	4/16/2007	SS	
Search Updated	8/22/2007	SS	
Search Updated	11/26/2007	SS	
NPL Documents Searched (ACM, INSPEC, IEEE)	12/4/2007	SS	

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner
345	87, 88	12/4/2007	SS
349	56,82,84,109,143,139	12/4/2007	SS